



Docket No.: 50090-332

Corres. and Mail
BOX AF

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Hisaya MORI, et al.

**RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE**

Application No.: 09/927,368

Filed: August 13, 2001

Customer No.: 20277
Confirmation No.: 4507

Group Art Unit: 2829

Examiner: J. M. Hollington

Title: APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR INTEGRATED
CIRCUIT

REQUEST FOR RECONSIDERATION UNDER 37 CFR 1.116

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This Request is submitted in response to the Office Action mailed August 12, 2004.

*Please
enter
J.M.H.*